

Product Change Notification - KSRA-20UFUA549

Date:

14 Jan 2019

Product Category:

8-bit Microcontrollers; Capacitive Touch Sensors

Affected CPNs:



Notification subject:

CCB 3368.001 Final Notice: Qualification of MMT as an additional assembly site for selected Atmel products of 35.4K, 35.5K and 19.6K available in 32L VQFN (5x5x0.9mm) package

Notification text:

PCN Status:

Final notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of MMT as an additional assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package

Pre Change:

Assembled at ANAC assembly site with punched as singulation method using 8290 die attach material

Post Change:

Assembled at ANAC assembly site with punched as singulation method using 8290 die attach material and Assembled at MMT assembly site with sawn as singulation method using 3280 die attach material

Pre and Post Change Summary:

	Pre Change	Post C	Change
Assembly Site	Amkor Assembly & Test (Shanghai) Co., LTD /	Amkor Assembly & Test (Shanghai) Co.,	Microchip Technology Thailand
	ANAC	LTD / ANAC	(Branch) / MMT
Wire material	Au	Au	Au
Die attach material	8290	8290	3280
Molding compound material	G700	G700	G700
Lead frame material	C194	C194	C194
Singulation Method	punched	punched	sawn

All inits in mil	llimeter (mm)		Assembly ai) Co., LTI	& rest	Microchip Technology Thailand (Branch) / MMT					
Dimensio	on Limits	Min	Nom	Max	Min	Nom	Max			
Number of terminals	N		32			32				
	е		0.50 BSC			0.50 BSC				



Pitch								
Overall Height	Α	0.8	0.85	0.9	0.8	0.9	1.0	
Standoff	A 1	0	0.01	0.05	0	0.02	0.05	
Molded package thickness	A2	0.6	0.65	0.7	N/A			
Terminal Thickness	А3	0.20 REF			0.203 REF			
Overall Length	D	5.00BSC			0.500 BSC			
Molded package length	D1	4.75BSC			N/A			
Overall Width	Е	5.00BSC			5.00 BSC			
Molded package Width	E1	4.75BSC			N/A			
Exposed Pad Length	D2	3.0	3.1	3.2	3.0	3.1	3.2	
Exposed Pad Width	E2	3.0	3.1	3.2	3.0	3.1	3.2	
Terminal Length	L	0.3	0.4	0.5	0.3	0.4	0.5	
Terminal-to- exposed- pad	К	0.2	1	-	0.2	ı	-	
Mold angle		0		12 ^O	N/A	N/A	N/A	
Package Chamfer	Р	0.24	0.42	0.6	N/A	N/A	N/A	
Exposed Tie Bar Length	Q	0.3	0.4	0.65	N/A	N/A	N/A	
Exposed Tie Bar Width	R	0.13	0.17	0.23	N/A	N/A	N/A	
POD Drawing		(PCN_KSI	ee attachme RA-20UFU hange_PO g_ANAC_Pi	A549_Pre- D	see attachment (PCN_KSRA-20UFUA549_Pre- Change_POD Drawing_MCHP_Sawn)			

The dimensions of the products from MMT are within the specifications of the package from ANAC. **Impacts to Data Sheet:**

Yes; Package outline drawing- change from punch version to saw singulated

Change Impact:

None

Reason for Change:

To improve productivity by qualifying MMT as an additional assembly site

Change Implementation Status:

In Progress



Estimated First Ship Date:

February 14, 2019 (date code: 1907)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

		Jan	uary 2	019	February 2019					
Workweek	01	02	03	04	05	06	07	80	09	
Qual Report Availability		Χ								
Final PCN Issue Date		Χ								
Estimated Implementation Date							Х			

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN # Qual Report.

Revision History:

January 14, 2019: Issued final notification. Attached the Qualification Report. Provided estimated first ship date on February 14, 2019.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN KSRA-20UFUA549 Qual Report.pdf
PCN KSRA-20UFUA549 Pre-Change POD Drawing ANAC Punched.pdf

PCN KSRA-20UFUA549 Post-Change POD Drawing MCHP Sawn.pdf

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN home page</u> select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

KSRA-20UFUA549 - CCB 3368.001 Final Notice: Qualification of MMT as an additional assembly site for selected Atmel products of 35.4K, 35.5K and 19.6K available in 32L VQFN (5x5x0.9mm) package

Affected Catalog Part Numbers (CPN)

AT42QT1244-MUR

AT42QT1245-MU

AT42QT1245-MUR

ATMEGA168-20MQ

ATMEGA168-20MQR

ATMEGA168-20MUR

ATMEGA168P-20MUR

ATMEGA168PA-MN

ATMEGA168PA-MNR

ATMEGA168PA-MUA1

ATMEGA168PA-MURA1

ATMEGA168PV-10MUR

ATMEGA168V-10MQ

ATMEGA168V-10MQR

ATMEGA168V-10MQR610

ATMEGA48A-MU

ATMEGA48A-MUR

ATMEGA48P-20MUR

ATMEGA48PA-MNR

ATMEGA48PA-MURA5

ATMEGA48V-10MUR

ATMEGA48V-10MURA3

ATMEGA88-20MUR

ATMEGA88PA-MN

ATMEGA88PA-MNR

ATMEGA88PA-MURA6

ATMEGA88V-10MURA1

ATMEGA8L-8MUA4

ATMEGA8L-8MURA3

ATMEGA8L-8MURA5

ATTINY26-16MQR

ATTINY261A-MF

ATTINY261A-MFR

ATTINY28L-4MU

ATTINY28V-1MU

ATTINY828-MU

ATTINY828-MUR

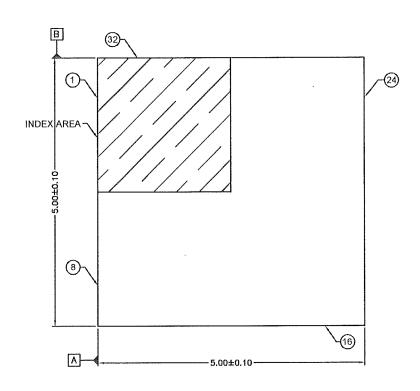
QT60160-ISG

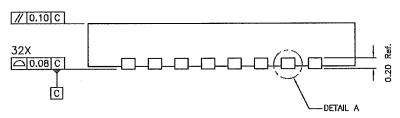
QT60240-ISG

Date: Sunday, January 13, 2019

REVISIONS										
REV.	DATE	DESCRIPTION	PROPOSED BY							
А	APR 11 17	NEW RELEASE	PRACHIT P.							

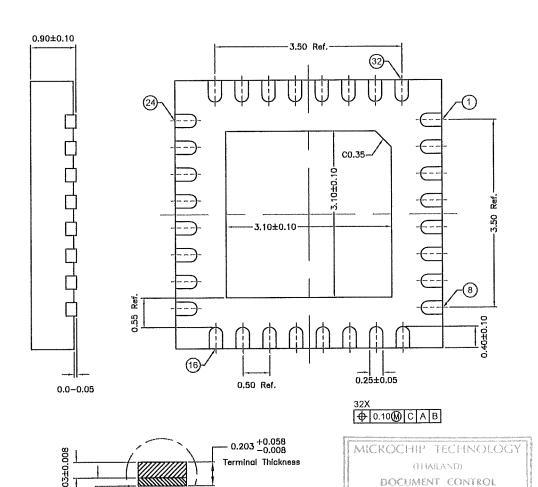
APR 18 2017





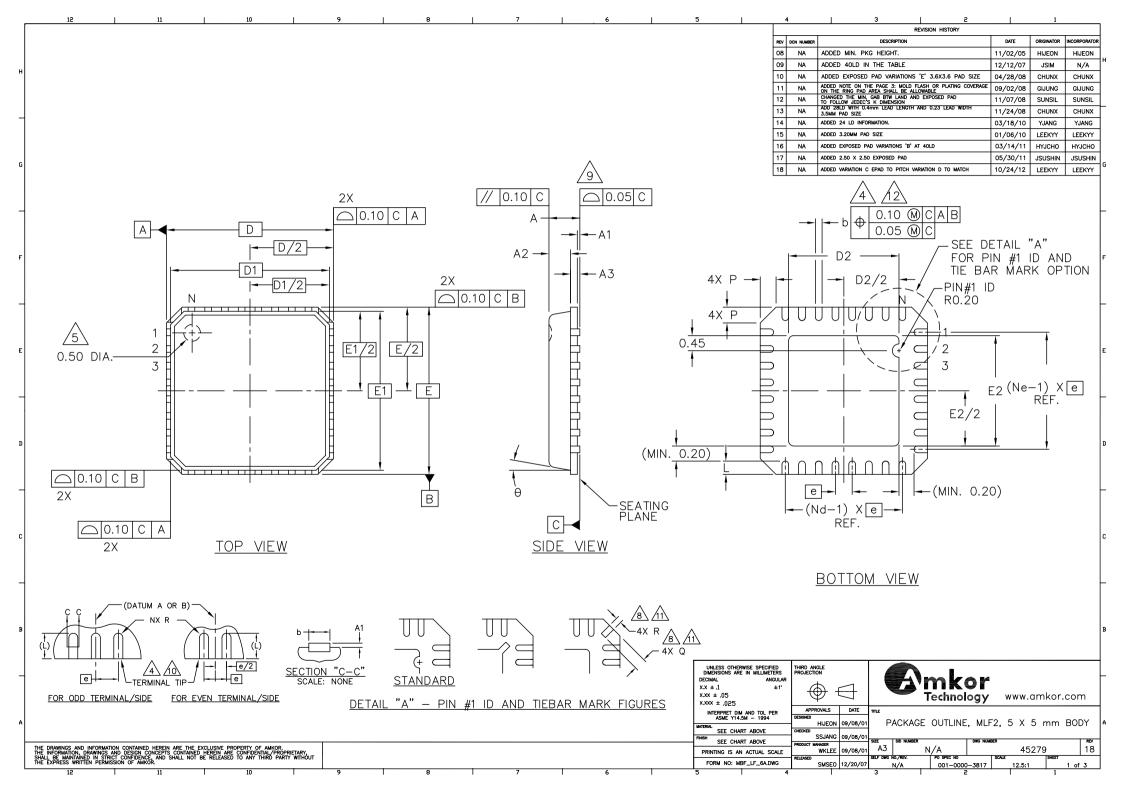
NOTE:

- 1. ALL DIMENSIONS ARE IN mm. ANGLES IN DEGREES.
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS. COPLANARITY SHALL NOT EXCEED 0.08 mm.
- 3. WARPAGE SHALL NOT EXCEED 0.10 mm.
- 4. PACKAGE LENGTH / PACKAGE WIDTH ARE CONSIDERED AS SPECIAL CHARACTERISTIC. (S)
- 5. REFER JEDEC MO-220.



UNLESS OTHER	VISE SPECIFIED	APPROVALS	BY // BY //	DATE	W.	Microchi	n Tach	noloay	, Thail	und		
1. ALL DIMENSIONS IN MM	6, LIMIT ON DIMENSION	DEPARTMENT MGR.	11871	Phh	Menoca	M icrochil	J IGVII	livivy	HIVII	UIIU		
2. DO NOT SCALE PRINTS	FRACTIONS	FOL	. DW	4/11/1	Title: 32L VQFN 5x5mm, pitch 0.5 mm, exposed pad 3.1x3.1 mm							
3. REMOVE ALL BURRS	DECIMAL	EOL	David	4/11/17	SCALE:	NONE	Sheet:	1	of:	1		
4. BREAK ALL CORNERS.	ANGULAR	TEST ENGR	MC	4/18/1	DRAW	CHECKED	CKED DRAWING No.			RE		
5. CONNER RADII,	7. SURFACE FINIAL				Wanut L.	PRACHIT P. B04-046			P			

DETAIL A



S M B O L	PITCH MIN.	VARIAT NOM.	TON A	N _O _{TE}	S Y M B O L	MIN.	VARIAT	MAX.	N _O _T _E	S Y M B O L	PITCH MIN.	VARIAT	TON C	N _O T _E	S Y M B O L	PITCH MIN.	VARIAT	MAX.	. N _O T _E
е	(0.80 BSC			е		0.65 BSC			е		0.65 BSC			e		0.50 BSC		
N		16		3	N		20		3	Ν		24		3	N		28		3
Nd		4		3	Nd		5		3	Nd		6		3	Nd		7		3
Ne		4		3	Ne		5		3	Ne		6		3	Ne		7		3
L	0.50	0.60	0.75		L	0.50	0.60	0.75		L	0.30	0.40	0.50		L	0.30	0.40	0.50	
b	0.28	0.33	0.40	4	b	0.23	0.28	0.35	4	b	0.23	0.28	0.35	4	b	0.18	0.23	0.30	4
D2 s	SEE EXPOSE	D PAD VAR	IATION: A,B		D2	SEE EXPOSE	D PAD VAR	IATION: A,B		D2	SEE EXPOS	SED PAD VAR	RIATION: F		D2	SEE EXPOS	SED PAD VAR	NATION: D	
E2	SEE EXPOSE	D PAD VAR	IATION: A,B		E2	SEE EXPOSE	D PAD VAR	IATION: A,B		E2	SEE EXPOS	SED PAD VAR	RIATION: F		E2	SEE EXPOS	SED PAD VAR	IATION: D	

S M B O L	PITCH MIN.	VARIATI NOM. I	ON D MAX.	N _O T _E	SYMBOL	PITCH MIN.	VARIAT	TON D MAX.	N _O T _E	SYMBOL	PITCH MIN.	VARIAT	TION E MAX.	N _O T _E	S Y M B O L	PITCH MIN.	VARIAT NOM. I	ION E	N _O T _E
e		0.50 BSC			е		0.50 BSC			е		0.40 BSC			е		0.40 BSC		
Ν		28		3	Ν		32		3	Z		36		3	Ν		40		3
Nd		7		3	Nd		8		3	Nd		9		3	Nd		10		3
Ne		7		3	Ne		8		3	Ne		9		3	Ne		10		3
L	0.50	0.60	0.75		L	0.30	0.40	0.50		L	0.30	0.40	0.50		L	0.30	0.40	0.50	
b	0.18	0.23	0.30	4	b	0.18	0.23	0.30	4	Ь	0.15	0.20	0.25	4,12	b	0.15	0.20	0.25	4,12
D2	SEE EXPOSE	D PAD VARIAT	ΠΟΝ: A,B,C,G		D2	SEE EXPOSE	D PAD VARIAT	ION: B,C,D,E,I		D2	SEE EXPOS	SED PAD VA	RIATION: *		D2	SEE EXPOSE	D PAD VARIA	ATION: B,D,E	
E2 9	SEE EXPOSEI	D PAD VARIAT	TION: A,B,C,G		E2	SEE EXPOSE	D PAD VARIAT	ION: B,C,D,E,I		E2	SEE EXPOS	SED PAD VA	RIATION: *				D PAD VARIA		

<STANDARD>

SYMBOLS			D2			E2		NOTE
		MIN	NOM	MAX	MIN	NOM	MAX	
	Α	2.60	2.70	2.80	2.60	2.70	2.80	
EXPOSED PAD VARIATIONS	В	2.70	2.80	2.90	2.70	2.80	2.90	
	С	3.00	3.10	3.20	3.00	3.10	3.20	
	D	3.20	3.30	3.40	3.20	3.30	3.40	
	Ε	3.40	3.50	3.60	3.40	3.50	3.60	
	F	3.50	3.60	3.70	3.50	3.60	3.70	
	G	2.70	2.80	2.90	2.70	2.80	2.90	

H 2.90 3.00 3.10 2.90 3.00 3.10 I 2.40 2.50 2.60 2.40 2.50 2.60

* NOT DESIGNED YET ** DESIGNED BUT NOT TOOLED UP

S		COMMON							
М В О	l DII	MENSION		N _O ,					
O	MIN.	NOM.	MAX.	TE					
Α	0.80	0.85	0.90						
A1	0.00	0.01	0.05	10					
A2	0.60	0.65	0.70						
А3		0.20 REF.	•						
D		5.00 BSC							
D1		4.75 BSC							
Ε		5.00 BSC							
E1		4.75 BSC							
θ	0		12°						
Р	0.24	0.42	0.60						
Q	0.30	0.40	0.65	8,11					
R	0.13	0.17	0.23	8,11					

GENERAL; NOMINAL EXPOSED PAD(D2/E2) DIMENSION = NOMINAL DIE ATTACH PAD DIMENSION-0.20

0.10 - NOMINAL DIE ATTACH PAD DIMENSION - 0.10

SDIE ATTACH PAD X-SECTION VIEW>

Emko Technolog	_
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PACKAGE OUTLINE, MLF2, 5 X 5 mm BODY

	-												
THE INFORMATION DRAWINGS AN	N CONTAINED HEREIN ARE THE EX ID DESIGN CONCEPTS CONTAINED	HEREIN ARE CONFIDENTIAL /PROPRI	ETARY,					PRINTING IS AN	ACTUAL SCALE	A3 SIZE SID NI	N/A		
SHALL BE MAINTAINED IN STRICT THE EXPRESS WRITTEN PERMISS	CONFIDENCE, AND SHALL NOT BOOK OF AMKOR.	E RELEASED TO ANY THIRD PARTY	WITHOUT					FORM NO: MB	F_LF_7A.DWG	SELF DWG NO./REV.	PO SPEC NO 001-00	00	

NOTES: 1. DIE THICKNESS ALLOWABLE IS 0.305mm MAXIMUM(.012 INCHES MAXIMUM) 2. DIMENSIONING & TOLERANCES CONFORM TO ASME Y14.5M. - 1994. 3. N IS THE NUMBER OF TERMINALS. Nd IS THE NUMBER OF TERMINALS IN X-DIRECTION & Ne IS THE NUMBER OF TERMINALS IN Y-DIRECTION. /4\ DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP. $/5 \! \setminus$ the pin #1 identifier must be existed on the top surface of the PACKAGE BY USING INDENTATION MARK OR OTHER FEATURE OF PACKAGE BODY. /6\ EXACT SHAPE AND SIZE OF THIS FEATURE IS OPTIONAL. 7. ALL DIMENSIONS ARE IN MILLIMETERS. /8), the shape shown on four corners are not actual 1/0. /9\ bilateral coplanarity zone applies to the exposed pad as well as the terminals. $\Lambda \wedge$ APPLIED ONLY FOR TERMINALS. $/\!\!\!\!/$ Q and R applies only for straght tiebar shapes. $\cancel{1}$ $\cancel{2}$. FOR 0.40mm LEAD PITCH, THE LEAD POSITION TOLERANCE MUST BE 0.07mm AT THE ACTUAL MEAN VALUE OF BODY SIZE. 13. MOLD FLASH OR PLATING COVERAGE ON THE RING PAD AREA SHALL BE ALLOWABLE



PACKAGE OUTLINE, MLF2, 5 X 5 mm BODY

PRINTING IS AN ACTUAL SCALE A3 N/A 45279

FORM NO: MBF_LF_7A.DWG SSLF UNION N/A 001-0000-3817 1:1 3 of



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN# KSRA-20UFUA549

Date October 18, 2018

Qualification of MMT as an additional assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package. The selected products of the 35.4K, 35.5K and 19.6K wafer technologies will qualify by similarity (QBS)



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose: Qualification of MMT as an additional assembly site for selected

Atmel products available in 32L VQFN (5x5x0.9mm) package. The selected products of the 35.4K, 35.5K and 19.6K wafer

technologies will qualify by similarity (QBS)

CCB No.: 3368 and 3368.001

Qual ID No.: QTP3485

Revision: A

CN	
BD Number BDM-001739 MP Code (MPC) 35473YRXBC01 Part Number (CPN) ATMEGA328P-MNR Paddle size 150x150 mils	
Part Number (CPN) ATMEGA328P-MNR Paddle size 150x150 mils	
Part Number (CPN) ATMEGA328P-MNR Paddle size 150x150 mils	
Paddle size 150x150 mils	
88-4-3-1	
Material C194	
Manufacturer ASM	
ଞ୍ଜି Surface Bare Cu on paddle	
다 Treatment BOT	
Manufacturer ASM Surface Bare Cu on paddle Treatment BOT Process Etched Lead-lock Yes	
Lead-lock Yes	
Part Number 10103202	
Lead Plating Matte Tin	
Material Au	
Part Number 3280 Conductive Yes	
Conductive Yes	
Part Number G700LTD	
PKG Type VQFN	
Pin/Ball Count 32	
PKG width/size 5x5x0.9mm	
Die Thickness 11 mils	
Die Size 115.5 x 114.2 mils	
Fab Process (site) 35.4K/MCSO	



Manufacturing Information:

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-190800274.000	MCSO519061142.000	1821PH7
MMT-190800275.000	MCSO519061142.000	1821PH8
MMT-190800276.000	MCSO519061142.000	1821PH9

Result		Pass [Fail			
	0100 0 0 0 0 0 1	for 201 VOEN 5	ν.Ε.ν.Ο. Οποιπο /D.V.Γ)\ = = A t == = 1	manducate at NANAT	المامسممم

Q100 Grade1 qual for 32L VQFN 5x5x0.9mm (RXB) on Atmel products at MMT assembly using 0.8 mil Au wire is qualified the Moisture/ Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard. No delamination were observed on all the units.

	PACKAGE QUALII	FICATIO	N RE	POR	Γ	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 1)	Electrical Test:+25°C, 130°C Bake 150°C, 24 hrs System: HERAEUS	JESD22- A113	876(0)	0/876 876	Passed	Good Devices
	85°C/85%RH Moisture Soak 168 hrs. System: Climats Excal 5423-HE 3x Convection-Reflow 265°C max System: Mancorp CR.5000F	IPC/JEDEC J-STD-020D		876 876	Passed	
	Electrical Test: +25°C, 130°C			0/876	Passed	
Temp Cycle	Stress Condition: (Standard) 65°C to +150°C, 500 Cycles System: VOTSCH VT 7012 S2 Electrical Test: +85°C, System: MAGNUM05 (Handtest)	JESD22- A104	243(0) 243(0)	0/243	Passed	Parts had been pre- conditioned at 260°C
	Bond Strength: Wire Pull (> 2.50 grams) Bond Shear (>15.00 grams)		15(0)	0/15	Passed	
UNBIASED- HAST	Stress Condition: (Standard) +130°C/85%RH, 96 hrs. System: HIRAYAMA HASTEST PC- 422R8	JESD22- A118	245(0)			Parts had been pre- conditioned at 260°C
	Electrical Test: +25°C, 130°C System: MT9510 Handler:2580		245(0)	0/245	Passed	
HAST	Stress Condition: (Standard) +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HIRAYAMA HASTEST PC- 422R8	JESD22- A110	237(0)			Parts had been pre- conditioned at 260°C
	Electrical Test: +25°C, 130°C System: MT9510 Handler:2580		237(0)	0/237	Passed	

	PACKAGE QUAL	IFICATIO	N R	EPOF	RT	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: HERAEUS	JESD22-A103	78(0)			78 units
3	Electrical Test: +25°C, 130°C		78(0)	0/78	Passed	
Solderability Temp 245°C	Bake: Temp 155°C,4Hrs System: Oven Solder Bath: Temp.245°C Solder material: SnPb Visual Inspection: External Visual Inspection	JESD22B- 102E	15 (0)	0/15	Passed	Performed at MPHIL
Physical Dimensions	Physical Dimension, 30 units from 1 lot	JESD22- B100/B108	30(0) Units	0/30	Passed	
Bond Strength	Wire Pull (> 2.50 grams)	M2011.8 MIL-STD-883	30(0) Wires	0/30	Passed	
Data Assembly	Bond Shear (>15.00 grams)	M2011.8 MIL-STD-883	30(0) bonds	0/30	Passed	